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## **SPECIFICATION**

- Supplier : Samsung electro-mechanics
- Product : Multi-layer Ceramic Capacitor
- Samsung P/N : CL31C101KBCNBNC
- Description : CAP, 100pF, 50V, ±10%, C0G, 1206

A. Samsung Part Number

			<u>CL</u> ①	<u>31</u> ②	<u>C</u> 3	<u>101</u> ④	<u>K</u> 5	<u>B</u> 6	<u>C</u> ⑦	<u>N</u> 8	<u>B</u> 9	<u>N</u> 10	<u>C</u> 11			
1	Series	Samsung	Multi-la	yer C	erami	ic Capa	acito	r								
2	Size	1206	(inch co	ode)		L:	3.2	± 0.1	5	mm		W:	1.6	± 0.15	mm	
3	Dielectric	C0G					8	Inne	r ele	ctrod	le		Ni			
4	Capacitance	100	рF					Tern	ninat	tion			Cu			
5	Capacitance	±10	%					Plati	ng				Sn 10	0%	(Pb Fre	e)
	tolerance						9	Proc	luct				Array	(4-elem	ent)	
6	Rated Voltage	50	V				10	Spee	cial				Reser	ved for	future us	se
$\bigcirc$	Thickness	0.85	± 0.15	mm			1	Pack	cagir	ng			Cardb	oard Ty	/pe, 7" re	el

## B. Samsung Reliablility Test and Judgement condition

	Performance	Test condition						
Capacitance	Within specified tolerance	1M±±10% 0.5~5Vrms						
Q	1000 min							
Insulation	10,000Mohm or 500Mohm⋅ <i>μ</i> F	Rated Voltage 60~120 sec.						
Resistance	Whichever is Smaller							
Appearance	No abnormal exterior appearance	Microscope (×10)						
Withstanding	No dielectric breakdown or	300% of the rated voltage						
Voltage	mechanical breakdown							
Temperature	C0G							
Characterisitcs	(From -55 $^\circ\!\!\mathbb{C}$ to 125 $^\circ\!\!\mathbb{C}$ , Capacitance change shoud be within ±30PPM/ $^\circ\!\!\mathbb{C}$ )							
Adhesive Strength	No peeling shall be occur on the	500g·F, for 10±1 sec.						
of Termination	terminal electrode							
Bending Strength	Capacitance change :	Bending to the limit (1mm)						
	within $\pm 5\%$ or $\pm 0.5$ pF whichever is larger	with 1.0mm/sec.						
Solderability	More than 75% of terminal surface	SnAg3.0Cu0.5 solder						
	is to be soldered newly	245±5℃, 3±0.3sec.						
		(preheating : 80~120℃ for 10~30sec.)						
Resistance to	Capacitance change :	Solder pot : 270±5℃, 10±1sec.						
Soldering heat	within $\pm 2.5\%$ or $\pm 0.25$ pF whichever is larger							
	Tan δ, IR : initial spec.							

	Performance	Test condition					
Vibration Test	Capacitance change :	Amplitude : 1.5mm					
	within ±2.5% or ±0.25pF whichever is larger	From 10Hz to 55Hz (return : 1min.)					
	Tan δ, IR : initial spec.	2hours $\times$ 3 direction (x, y, z)					
Moisture	Capacitance change :	With rated voltage					
Resistance	within ±7.5% or ±0.75pF whichever is larger	40±2℃, 90~95%RH, 500+12/-0hrs					
	Q : 200 min						
	IR : 500Mohm or 25Mohm · μF						
	Whichever is Smaller						
High Temperature	Capacitance change :	With 200% of the rated voltage					
Resistance	within ±3% or ±0.3pF whichever is larger	Max. operating temperature					
	Q : 350 min	1000+48/-0hrs					
	IR : 1000Mohm or 50Mohm $\cdot \mu F$						
	Whichever is Smaller						
Temperature	Capacitance change :	1 cycle condition					
Cycling	within ±2.5% or ±0.25pF whichever is larger	Min. operating temperature $\rightarrow$ 25 °C					
	Tan δ, IR : initial spec.	$\rightarrow$ Max. operating temperature $\rightarrow$ 25 °C					
		5 cycle test					

## C. Recommended Soldering method :

Reflow ( Reflow Peak Temperature : 260+0/-5°C, 10sec. Max )

\* For the more detail Specification, Please refer to the Samsung MLCC catalogue.